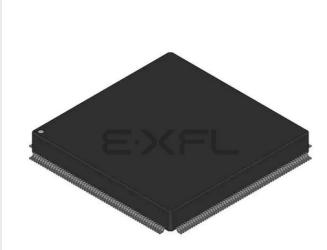
E·XFL

Altera - EP20K100QC240-3V Datasheet



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Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Details	
Product Status	Active
Number of LABs/CLBs	416
Number of Logic Elements/Cells	4160
Total RAM Bits	53248
Number of I/O	189
Number of Gates	263000
Voltage - Supply	2.375V ~ 2.625V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	240-BFQFP
Supplier Device Package	240-PQFP (32x32)
Purchase URL	https://www.e-xfl.com/pro/item?MUrl=&PartUrl=ep20k100qc240-3v

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

- Flexible clock management circuitry with up to four phase-locked loops (PLLs)
 - Built-in low-skew clock tree
 - Up to eight global clock signals
 - ClockLock[®] feature reducing clock delay and skew
 - ClockBoost[®] feature providing clock multiplication and division
 - ClockShiftTM programmable clock phase and delay shifting
- Powerful I/O features
 - Compliant with peripheral component interconnect Special Interest Group (PCI SIG) *PCI Local Bus Specification, Revision 2.2* for 3.3-V operation at 33 or 66 MHz and 32 or 64 bits
 - Support for high-speed external memories, including DDR SDRAM and ZBT SRAM (ZBT is a trademark of Integrated Device Technology, Inc.)
 - Bidirectional I/O performance $(t_{CO} + t_{SU})$ up to 250 MHz
 - LVDS performance up to 840 Mbits per channel
 - Direct connection from I/O pins to local interconnect providing fast t_{CO} and t_{SU} times for complex logic
 - MultiVolt I/O interface support to interface with 1.8-V, 2.5-V, 3.3-V, and 5.0-V devices (see Table 3)
 - Programmable clamp to V_{CCIO}
 - Individual tri-state output enable control for each pin
 - Programmable output slew-rate control to reduce switching noise
 - Support for advanced I/O standards, including low-voltage differential signaling (LVDS), LVPECL, PCI-X, AGP, CTT, stubseries terminated logic (SSTL-3 and SSTL-2), Gunning transceiver logic plus (GTL+), and high-speed terminated logic (HSTL Class I)
 - Pull-up on I/O pins before and during configuration
- Advanced interconnect structure
 - Four-level hierarchical FastTrack[®] Interconnect structure providing fast, predictable interconnect delays
 - Dedicated carry chain that implements arithmetic functions such as fast adders, counters, and comparators (automatically used by software tools and megafunctions)
 - Dedicated cascade chain that implements high-speed, high-fan-in logic functions (automatically used by software tools and megafunctions)
 - Interleaved local interconnect allows one LE to drive 29 other LEs through the fast local interconnect
- Advanced packaging options
 - Available in a variety of packages with 144 to 1,020 pins (see Tables 4 through 7)
 - FineLine BGA[®] packages maximize board space efficiency
- Advanced software support
 - Software design support and automatic place-and-route provided by the Altera[®] Quartus[®] II development system for

Normal Mode

The normal mode is suitable for general logic applications, combinatorial functions, or wide decoding functions that can take advantage of a cascade chain. In normal mode, four data inputs from the LAB local interconnect and the carry-in are inputs to a four-input LUT. The Quartus II software Compiler automatically selects the carry-in or the DATA3 signal as one of the inputs to the LUT. The LUT output can be combined with the cascade-in signal to form a cascade chain through the cascade-out signal. LEs in normal mode support packed registers.

Arithmetic Mode

The arithmetic mode is ideal for implementing adders, accumulators, and comparators. An LE in arithmetic mode uses two 3-input LUTs. One LUT computes a three-input function; the other generates a carry output. As shown in Figure 8, the first LUT uses the carry-in signal and two data inputs from the LAB local interconnect to generate a combinatorial or registered output. For example, when implementing an adder, this output is the sum of three signals: DATA1, DATA2, and carry-in. The second LUT uses the same three signals to generate a carry-out signal, thereby creating a carry chain. The arithmetic mode also supports simultaneous use of the cascade chain. LEs in arithmetic mode can drive out registered and unregistered versions of the LUT output.

The Quartus II software implements parameterized functions that use the arithmetic mode automatically where appropriate; the designer does not need to specify how the carry chain will be used.

Counter Mode

The counter mode offers clock enable, counter enable, synchronous up/down control, synchronous clear, and synchronous load options. The counter enable and synchronous up/down control signals are generated from the data inputs of the LAB local interconnect. The synchronous clear and synchronous load options are LAB-wide signals that affect all registers in the LAB. Consequently, if any of the LEs in an LAB use the counter mode, other LEs in that LAB must be used as part of the same counter or be used for a combinatorial function. The Quartus II software automatically places any registers that are not used by the counter into other LABs.



Figure 10. FastTrack Connection to Local Interconnect

Read/Write Clock Mode

The read/write clock mode contains two clocks. One clock controls all registers associated with writing: data input, WE, and write address. The other clock controls all registers associated with reading: read enable (RE), read address, and data output. The ESB also supports clock enable and asynchronous clear signals; these signals also control the read and write registers independently. Read/write clock mode is commonly used for applications where reads and writes occur at different system frequencies. Figure 20 shows the ESB in read/write clock mode.



Figure 20. ESB in Read/Write Clock Mode Note (1)

Notes to Figure 20:

- All registers can be cleared asynchronously by ESB local interconnect signals, global signals, or the chip-wide reset. (1)
- APEX 20KE devices have four dedicated clocks. (2)

Input/Output Clock Mode

The input/output clock mode contains two clocks. One clock controls all registers for inputs into the ESB: data input, WE, RE, read address, and write address. The other clock controls the ESB data output registers. The ESB also supports clock enable and asynchronous clear signals; these signals also control the reading and writing of registers independently. Input/output clock mode is commonly used for applications where the reads and writes occur at the same system frequency, but require different clock enable signals for the input and output registers. Figure 21 shows the ESB in input/output clock mode.

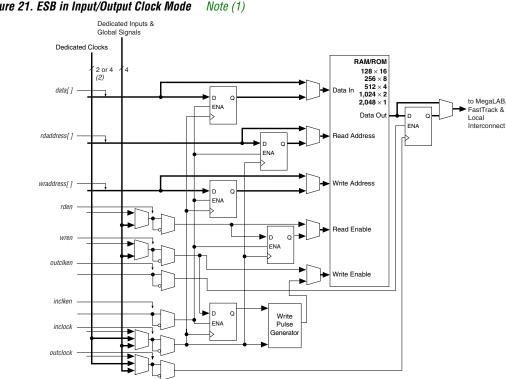


Figure 21. ESB in Input/Output Clock Mode

Notes to Figure 21:

All registers can be cleared asynchronously by ESB local interconnect signals, global signals, or the chip-wide reset. (1)APEX 20KE devices have four dedicated clocks. (2)

Single-Port Mode

The APEX 20K ESB also supports a single-port mode, which is used when simultaneous reads and writes are not required. See Figure 22.

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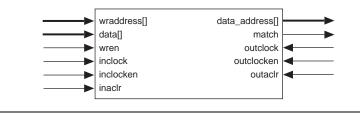


Figure 23. APEX 20KE CAM Block Diagram

CAM can be used in any application requiring high-speed searches, such as networking, communications, data compression, and cache management.

The APEX 20KE on-chip CAM provides faster system performance than traditional discrete CAM. Integrating CAM and logic into the APEX 20KE device eliminates off-chip and on-chip delays, improving system performance.

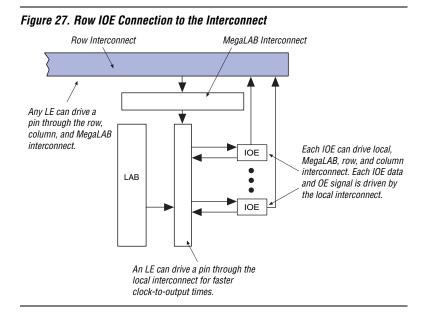
When in CAM mode, the ESB implements 32-word, 32-bit CAM. Wider or deeper CAM can be implemented by combining multiple CAMs with some ancillary logic implemented in LEs. The Quartus II software combines ESBs and LEs automatically to create larger CAMs.

CAM supports writing "don't care" bits into words of the memory. The "don't-care" bit can be used as a mask for CAM comparisons; any bit set to "don't-care" has no effect on matches.

The output of the CAM can be encoded or unencoded. When encoded, the ESB outputs an encoded address of the data's location. For instance, if the data is located in address 12, the ESB output is 12. When unencoded, the ESB uses its 16 outputs to show the location of the data over two clock cycles. In this case, if the data is located in address 12, the 12th output line goes high. When using unencoded outputs, two clock cycles are required to read the output because a 16-bit output bus is used to show the status of 32 words.

The encoded output is better suited for designs that ensure duplicate data is not written into the CAM. If duplicate data is written into two locations, the CAM's output will be incorrect. If the CAM may contain duplicate data, the unencoded output is a better solution; CAM with unencoded outputs can distinguish multiple data locations.

CAM can be pre-loaded with data during configuration, or it can be written during system operation. In most cases, two clock cycles are required to write each word into CAM. When "don't-care" bits are used, a third clock cycle is required. Each IOE drives a row, column, MegaLAB, or local interconnect when used as an input or bidirectional pin. A row IOE can drive a local, MegaLAB, row, and column interconnect; a column IOE can drive the column interconnect. Figure 27 shows how a row IOE connects to the interconnect.



Advanced I/O Standard Support

APEX 20KE IOEs support the following I/O standards: LVTTL, LVCMOS, 1.8-V I/O, 2.5-V I/O, 3.3-V PCI, PCI-X, 3.3-V AGP, LVDS, LVPECL, GTL+, CTT, HSTL Class I, SSTL-3 Class I and II, and SSTL-2 Class I and II.



For more information on I/O standards supported by APEX 20KE devices, see *Application Note* 117 (*Using Selectable I/O Standards in Altera Devices*).

The APEX 20KE device contains eight I/O banks. In QFP packages, the banks are linked to form four I/O banks. The I/O banks directly support all standards except LVDS and LVPECL. All I/O banks can support LVDS and LVPECL with the addition of external resistors. In addition, one block within a bank contains circuitry to support high-speed True-LVDS and LVPECL inputs, and another block within a particular bank supports high-speed True-LVDS and LVPECL outputs. The LVDS blocks support all of the I/O standards. Each I/O bank has its own VCCIO pins. A single device can support 1.8-V, 2.5-V, and 3.3-V interfaces; each bank can support a different standard independently. Each bank can also use a separate V_{REF} level so that each bank can support any of the terminated standards (such as SSTL-3) independently. Within a bank, any one of the terminated standards can be supported. EP20K300E and larger APEX 20KE devices support the LVDS interface for data pins (smaller devices support LVDS clock pins, but not data pins). All EP20K300E and larger devices support the LVDS interface for data pins up to 155 Mbit per channel; EP20K400E devices and larger with an X-suffix on the ordering code add a serializer/deserializer circuit and PLL for higher-speed support.

Each bank can support multiple standards with the same VCCIO for output pins. Each bank can support one voltage-referenced I/O standard, but it can support multiple I/O standards with the same VCCIO voltage level. For example, when VCCIO is 3.3 V, a bank can support LVTTL, LVCMOS, 3.3-V PCI, and SSTL-3 for inputs and outputs.

When the LVDS banks are not used as LVDS I/O banks, they support all of the other I/O standards. Figure 29 shows the arrangement of the APEX 20KE I/O banks.

Under hot socketing conditions, APEX 20KE devices will not sustain any damage, but the I/O pins will drive out.

MultiVolt I/O Interface

The APEX device architecture supports the MultiVolt I/O interface feature, which allows APEX devices in all packages to interface with systems of different supply voltages. The devices have one set of VCC pins for internal operation and input buffers (VCCINT), and another set for I/O output drivers (VCCIO).

The APEX 20K VCCINT pins must always be connected to a 2.5 V power supply. With a 2.5-V V_{CCINT} level, input pins are 2.5-V, 3.3-V, and 5.0-V tolerant. The VCCIO pins can be connected to either a 2.5-V or 3.3-V power supply, depending on the output requirements. When VCCIO pins are connected to a 2.5-V power supply, the output levels are compatible with 2.5-V systems. When the VCCIO pins are connected to a 3.3-V power supply, the output high is 3.3 V and is compatible with 3.3-V or 5.0-V systems.

Table 12. 5.0-V Tolerant APEX 20K MultiVolt I/O Support									
V _{CCIO} (V)	V _{CCIO} (V) Input Signals (V) Output Signals (V)								
-	2.5	3.3	5.0	2.5	3.3	5.0			
2.5	\checkmark	√(1)	√ (1)	✓					
3.3	\checkmark	\checkmark	√ (1)	√ (2)	\checkmark	 Image: A start of the start of			

Table 12 summarizes 5.0-V tolerant APEX 20K MultiVolt I/O support.

Notes to Table 12:

- The PCI clamping diode must be disabled to drive an input with voltages higher than V_{CCIO}.
- (2) When $V_{CCIO} = 3.3 \text{ V}$, an APEX 20K device can drive a 2.5-V device with 3.3-V tolerant inputs.

Open-drain output pins on 5.0-V tolerant APEX 20K devices (with a pullup resistor to the 5.0-V supply) can drive 5.0-V CMOS input pins that require a V_{IH} of 3.5 V. When the pin is inactive, the trace will be pulled up to 5.0 V by the resistor. The open-drain pin will only drive low or tri-state; it will never drive high. The rise time is dependent on the value of the pullup resistor and load impedance. The I_{OL} current specification should be considered when selecting a pull-up resistor.

Symbol	Parameter	Min	Max	Unit
t _{SKEW}	Skew delay between related ClockLock/ClockBoost-generated clocks		500	ps
JITTER	Jitter on ClockLock/ClockBoost-generated clock (5)		200	ps
t _{INCLKSTB}	Input clock stability (measured between adjacent clocks)		50	ps

Notes to Table 15:

- (1) The PLL input frequency range for the EP20K100-1X device for 1x multiplication is 25 MHz to 175 MHz.
- (2) All input clock specifications must be met. The PLL may not lock onto an incoming clock if the clock specifications are not met, creating an erroneous clock within the device.
- (3) During device configuration, the ClockLock and ClockBoost circuitry is configured first. If the incoming clock is supplied during configuration, the ClockLock and ClockBoost circuitry locks during configuration, because the lock time is less than the configuration time.
- (4) The jitter specification is measured under long-term observation.
- (5) If the input clock stability is 100 ps, t_{JITTER} is 250 ps.

Table 16 summarizes the APEX 20K ClockLock and ClockBoost parameters for -2 speed grade devices.

Symbol	Parameter	Min	Max	Unit		
f _{out}	Output frequency	25	170	MHz		
f _{CLK1}	Input clock frequency (ClockBoost clock multiplication factor equals 1)	25	170	MHz		
f _{CLK2}	Input clock frequency (ClockBoost clock multiplication factor equals 2)	Image: Construction open structure Image: Constructure Image				
f _{CLK4}	Input clock frequency (ClockBoost clock multiplication factor equals 4)	10	34	MHz		
t _{OUTDUTY}	Duty cycle for ClockLock/ClockBoost-generated clock	40	60	%		
f _{CLKDEV}	Input deviation from user specification in the Quartus II software (ClockBoost clock multiplication factor equals one) (1)		25,000 (2)	PPM		
t _R	Input rise time		5	ns		
t _F	Input fall time		5	ns		
t _{LOCK}	Time required for ClockLock/ ClockBoost to acquire lock (3)		10	μs		
t _{SKEW}	Skew delay between related ClockLock/ ClockBoost- generated clock	500	500	ps		
t _{JITTER}	Jitter on ClockLock/ ClockBoost-generated clock (4)		200	ps		
t _{INCLKSTB}	Input clock stability (measured between adjacent clocks)		50	ps		

Table 16. APEX 20K ClockLock & ClockBoost Parameters for -2 Speed Grade Devices

Table 2	8. APEX 20KE Device Recommende	ed Operating Conditions			
Symbol	Parameter	Conditions	Min	Max	Unit
V _{CCINT}	Supply voltage for internal logic and input buffers	(3), (4)	1.71 (1.71)	1.89 (1.89)	V
V _{CCIO}	Supply voltage for output buffers, 3.3-V operation	(3), (4)	3.00 (3.00)	3.60 (3.60)	V
	Supply voltage for output buffers, 2.5-V operation	(3), (4)	2.375 (2.375)	2.625 (2.625)	V
	Supply voltage for output buffers, 1.8-V operation	(3), (4)	1.71 (1.71)	1.89 (1.89)	V
VI	Input voltage	(5), (6)	-0.5	4.0	V
Vo	Output voltage		0	V _{CCIO}	V
ТJ	Junction temperature	For commercial use	0	85	°C
		For industrial use	-40	100	°C
t _R	Input rise time			40	ns
t _F	Input fall time			40	ns

Table 31. APEX 2	Table 31. APEX 20K f _{MAX} Timing Parameters (Part 2 of 2)					
Symbol	Parameter					
t _{ESBDATACO2}	ESB clock-to-output delay without output registers					
t _{ESBDD}	ESB data-in to data-out delay for RAM mode					
t _{PD}	ESB macrocell input to non-registered output					
t _{PTERMSU}	ESB macrocell register setup time before clock					
t _{PTERMCO}	ESB macrocell register clock-to-output delay					
t _{F1-4}	Fanout delay using local interconnect					
t _{F5-20}	Fanout delay using MegaLab Interconnect					
t _{F20+}	Fanout delay using FastTrack Interconnect					
t _{CH}	Minimum clock high time from clock pin					
t _{CL}	Minimum clock low time from clock pin					
t _{CLRP}	LE clear pulse width					
t _{PREP}	LE preset pulse width					
t _{ESBCH}	Clock high time					
t _{ESBCL}	Clock low time					
t _{ESBWP}	Write pulse width					
t _{ESBRP}	Read pulse width					

Tables 32 and 33 describe APEX 20K external timing parameters.

Table 32. APEX 20K External Timing Parameters Note (1)					
Symbol	Clock Parameter				
t _{INSU}	Setup time with global clock at IOE register				
t _{INH}	Hold time with global clock at IOE register				
t _{оитсо}	Clock-to-output delay with global clock at IOE register				

Table 33. APEX 20K External Bidirectional Timing Parameters Note (1)							
Symbol	Parameter	Conditions					
t _{INSUBIDIR}	Setup time for bidirectional pins with global clock at same-row or same-column LE register						
t _{INHBIDIR}	Hold time for bidirectional pins with global clock at same-row or same-column LE register						
^t OUTCOBIDIR	Clock-to-output delay for bidirectional pins with global clock at IOE register	C1 = 10 pF					
t _{XZBIDIR}	Synchronous IOE output buffer disable delay	C1 = 10 pF					
t _{ZXBIDIR}	Synchronous IOE output buffer enable delay, slow slew rate = off	C1 = 10 pF					

Symbol	Parameter	Conditions
t _{INSUBIDIR}	Setup time for bidirectional pins with global clock at LAB adjacent Input Register	
t _{INHBIDIR}	Hold time for bidirectional pins with global clock at LAB adjacent Input Register	
^t OUTCOBIDIR	Clock-to-output delay for bidirectional pins with global clock at IOE output register	C1 = 10 pF
t _{XZBIDIR}	Synchronous Output Enable Register to output buffer disable delay	C1 = 10 pF
t _{ZXBIDIR}	Synchronous Output Enable Register output buffer enable delay	C1 = 10 pF
^t INSUBIDIRPLL	Setup time for bidirectional pins with PLL clock at LAB adjacent Input Register	
t _{INHBIDIRPLL}	Hold time for bidirectional pins with PLL clock at LAB adjacent Input Register	
^t OUTCOBIDIRPLL	Clock-to-output delay for bidirectional pins with PLL clock at IOE output register	C1 = 10 pF
t _{XZBIDIRPLL}	Synchronous Output Enable Register to output buffer disable delay with PLL	C1 = 10 pF
t _{ZXBIDIRPLL}	Synchronous Output Enable Register output buffer enable delay with PLL	C1 = 10 pF

Note to Tables 38 and 39:

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(1) These timing parameters are sample-tested only.

Symbol	-1 Spee	d Grade	-2 Speed Grade		-3 Speed Grade		Units
					_		-
	Min	Max	Min	Max	Min	Max	
t _{SU}	0.1		0.3		0.6		ns
t _H	0.5		0.8		0.9		ns
t _{CO}		0.1		0.4		0.6	ns
t _{LUT}		1.0		1.2		1.4	ns
t _{ESBRC}		1.7		2.1		2.4	ns
t _{ESBWC}		5.7		6.9		8.1	ns
t _{ESBWESU}	3.3		3.9		4.6		ns
t _{ESBDATASU}	2.2		2.7		3.1		ns
t _{ESBDATAH}	0.6		0.8		0.9		ns
t _{ESBADDRSU}	2.4		2.9		3.3		ns
t _{ESBDATACO1}		1.3		1.6		1.8	ns
t _{ESBDATACO2}		2.5		3.1		3.6	ns
t _{ESBDD}		2.5		3.3		3.6	ns
t _{PD}		2.5		3.1		3.6	ns
t _{PTERMSU}	1.7		2.1		2.4		ns
t _{PTERMCO}		1.0		1.2		1.4	ns
t _{F1-4}		0.4		0.5		0.6	ns
t _{F5-20}		2.6		2.8		2.9	ns
t _{F20+}		3.7		3.8		3.9	ns
t _{CH}	2.0		2.5		3.0		ns
t _{CL}	2.0		2.5		3.0		ns
t _{CLRP}	0.5		0.6		0.8		ns
t _{PREP}	0.5		0.5		0.5		ns
t _{ESBCH}	2.0		2.5		3.0		ns
t _{ESBCL}	2.0		2.5		3.0		ns
t _{ESBWP}	1.5		1.9		2.2		ns
t _{ESBRP}	1.0		1.2		1.4		ns

Tables 43 through 48 show the I/O external and external bidirectional timing parameter values for EP20K100, EP20K200, and EP20K400 APEX 20K devices.

Symbol	-	1		-2	-3		Unit
	Min	Max	Min	Max	Min	Max	
t _{ESBARC}		2.03		2.86		4.24	ns
t _{ESBSRC}		2.58		3.49		5.02	ns
t _{ESBAWC}		3.88		5.45		8.08	ns
t _{ESBSWC}		4.08		5.35		7.48	ns
t _{ESBWASU}	1.77		2.49		3.68		ns
t _{ESBWAH}	0.00		0.00		0.00		ns
t _{ESBWDSU}	1.95		2.74		4.05		ns
t _{ESBWDH}	0.00		0.00		0.00		ns
t _{ESBRASU}	1.96		2.75		4.07		ns
t _{ESBRAH}	0.00		0.00		0.00		ns
t _{ESBWESU}	1.80		2.73		4.28		ns
t _{ESBWEH}	0.00		0.00		0.00		ns
t _{ESBDATASU}	0.07		0.48		1.17		ns
t _{ESBDATAH}	0.13		0.13		0.13		ns
t _{ESBWADDRSU}	0.30		0.80		1.64		ns
t _{ESBRADDRSU}	0.37		0.90		1.78		ns
t _{ESBDATACO1}		1.11		1.32		1.67	ns
t _{ESBDATACO2}		2.65		3.73		5.53	ns
t _{ESBDD}		3.88		5.45		8.08	ns
t _{PD}		1.91		2.69		3.98	ns
t _{PTERMSU}	1.04		1.71		2.82		ns
t _{PTERMCO}		1.13		1.34		1.69	ns

Table 51. EP20K30E f_{MAX} Routing Delays

Symbol	-1		/mbol -1 -2		-2	-9	}	Unit
	Min	Max	Min	Max	Min	Max		
t _{F1-4}		0.24		0.27		0.31	ns	
t _{F5-20}		1.03		1.14		1.30	ns	
t _{F20+}		1.42		1.54		1.77	ns	

Symbol	-	1	-	2	-:	3	Unit
	Min	Max	Min	Max	Min	Max	
t _{ESBARC}		1.61		1.84		1.97	ns
t _{ESBSRC}		2.57		2.97		3.20	ns
t _{ESBAWC}		0.52		4.09		4.39	ns
t _{ESBSWC}		3.17		3.78		4.09	ns
t _{ESBWASU}	0.56		6.41		0.63		ns
t _{ESBWAH}	0.48		0.54		0.55		ns
t _{ESBWDSU}	0.71		0.80		0.81		ns
t _{ESBWDH}	.048		0.54		0.55		ns
t _{ESBRASU}	1.57		1.75		1.87		ns
t _{ESBRAH}	0.00		0.00		0.20		ns
t _{ESBWESU}	1.54		1.72		1.80		ns
t _{ESBWEH}	0.00		0.00		0.00		ns
t _{ESBDATASU}	-0.16		-0.20		-0.20		ns
t _{ESBDATAH}	0.13		0.13		0.13		ns
t _{ESBWADDRSU}	0.12		0.08		0.13		ns
t _{ESBRADDRSU}	0.17		0.15		0.19		ns
t _{ESBDATACO1}		1.20		1.39		1.52	ns
t _{ESBDATACO2}		2.54		2.99		3.22	ns
t _{ESBDD}		3.06		3.56		3.85	ns
t _{PD}		1.73		2.02		2.20	ns
t _{PTERMSU}	1.11		1.26		1.38		ns
t _{PTERMCO}		1.19		1.40		1.08	ns

Table 63. EP2	OK100E f _{max} i	Routing Delay	S				
Symbol	-	1		-2	-;	3	Unit
	Min	Max	Min	Max	Min	Мах	
t _{F1-4}		0.24		0.27		0.29	ns
t _{F5-20}		1.04		1.26		1.52	ns
t _{F20+}		1.12		1.36		1.86	ns

Symbol	-1		-2		-3		Unit
	Min	Max	Min	Мах	Min	Max	
t _{insubidir}	2.86		3.24		3.54		ns
t _{inhbidir}	0.00		0.00		0.00		ns
t _{outcobidir}	2.00	5.07	2.00	5.59	2.00	6.13	ns
t _{xzbidir}		7.43		8.23		8.58	ns
tzxbidir		7.43		8.23		8.58	ns
t _{insubidirpll}	4.93		5.48		-		ns
t _{inhbidirpll}	0.00		0.00		-		ns
toutcobidirpll	0.50	3.00	0.50	3.35	-	-	ns
t _{XZBIDIRPLL}		5.36		5.99		-	ns
t _{ZXBIDIRPLL}		5.36		5.99		-	ns

Tables 73 through 78 describe f_{MAX} LE Timing Microparameters, f_{MAX} ESB Timing Microparameters, f_{MAX} Routing Delays, Minimum Pulse Width Timing Parameters, External Timing Parameters, and External Bidirectional Timing Parameters for EP20K200E APEX 20KE devices.

Table 73. EP2	Table 73. EP20K200E f _{MAX} LE Timing Microparameters										
Symbol	-	1		-2		3	Unit				
	Min	Max	Min	Max	Min	Мах					
t _{SU}	0.23		0.24		0.26		ns				
t _H	0.23		0.24		0.26		ns				
t _{CO}		0.26		0.31		0.36	ns				
t _{LUT}		0.70		0.90		1.14	ns				

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Symbol	-	1	-	2		3	Unit
	Min	Max	Min	Max	Min	Max	
t _{ESBARC}		1.79		2.44		3.25	ns
t _{ESBSRC}		2.40		3.12		4.01	ns
t _{ESBAWC}		3.41		4.65		6.20	ns
t _{ESBSWC}		3.68		4.68		5.93	ns
t _{ESBWASU}	1.55		2.12		2.83		ns
t _{ESBWAH}	0.00		0.00		0.00		ns
t _{ESBWDSU}	1.71		2.33		3.11		ns
t _{ESBWDH}	0.00		0.00		0.00		ns
t _{ESBRASU}	1.72		2.34		3.13		ns
t _{ESBRAH}	0.00		0.00		0.00		ns
t _{ESBWESU}	1.63		2.36		3.28		ns
t _{ESBWEH}	0.00		0.00		0.00		ns
t _{ESBDATASU}	0.07		0.39		0.80		ns
t _{ESBDATAH}	0.13		0.13		0.13		ns
t _{ESBWADDRSU}	0.27		0.67		1.17		ns
t _{ESBRADDRSU}	0.34		0.75		1.28		ns
t _{ESBDATACO1}		1.03		1.20		1.40	ns
t _{ESBDATACO2}		2.33		3.18		4.24	ns
t _{ESBDD}		3.41		4.65		6.20	ns
t _{PD}		1.68		2.29		3.06	ns
t _{PTERMSU}	0.96		1.48		2.14		ns
t _{PTERMCO}		1.05		1.22		1.42	ns

Table 81. EP2	OK300E f _{MAX}	Routing Delays	S				
Symbol	-	1		-2	-;	3	Unit
	Min	Max	Min	Max	Min	Мах	
t _{F1-4}		0.22		0.24		0.26	ns
t _{F5-20}		1.33		1.43		1.58	ns
t _{F20+}		3.63		3.93		4.35	ns

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Symbol	-1 Speed Grade		-2 Spee	-2 Speed Grade		-3 Speed Grade		
	Min	Max	Min	Max	Min	Max		
t _{CH}	2.00		2.50		2.75		ns	
t _{CL}	2.00		2.50		2.75		ns	
t _{CLRP}	0.18		0.26		0.34		ns	
t _{PREP}	0.18		0.26		0.34		ns	
t _{ESBCH}	2.00		2.50		2.75		ns	
t _{ESBCL}	2.00		2.50		2.75		ns	
t _{ESBWP}	1.17		1.68		2.18		ns	
t _{ESBRP}	0.95		1.35		1.76		ns	

Symbol	-1 Speed Grade		-2 Speed Grade		-3 Speed	Unit	
	Min	Max	Min	Max	Min	Max	
t _{INSU}	2.74		2.74		2.87		ns
t _{INH}	0.00		0.00		0.00		ns
toutco	2.00	5.51	2.00	6.06	2.00	6.61	ns
tINSUPLL	1.86		1.96		-		ns
t _{INHPLL}	0.00		0.00		-		ns
toutcopll	0.50	2.62	0.50	2.91	-	-	ns

Symbol	-1 Speed Grade		-2 Speed Grade		-3 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	
t _{insubidir}	0.64		0.98		1.08		ns
t _{inhbidir}	0.00		0.00		0.00		ns
t _{outcobidir}	2.00	5.51	2.00	6.06	2.00	6.61	ns
t _{xzbidir}		6.10		6.74		7.10	ns
t _{zxbidir}		6.10		6.74		7.10	ns
t _{insubidirpll}	2.26		2.68		-		ns
t _{inhbidirpll}	0.00		0.00		-		ns
toutcobidirpll	0.50	2.62	0.50	2.91	-	-	ns
t _{xzbidirpll}		3.21		3.59		-	ns
t _{ZXBIDIRPLL}		3.21		3.59		-	ns

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Table 99. EP2	OK1000E f _{MAX}	Routing Dela	ys				
Symbol	-1 Spee	d Grade	-2 Spe	ed Grade	-3 Spee	d Grade	Unit
	Min	Max	Min	Max	Min	Max	
t _{F1-4}		0.27		0.27		0.27	ns
t _{F5-20}		1.45		1.63		1.75	ns
t _{F20+}		4.15		4.33		4.97	ns

Symbol	-1 Speed Grade		-2 Speed Grade		-3 Spee	Unit	
	Min	Max	Min	Max	Min	Max]
t _{CH}	1.25		1.43		1.67		ns
t _{CL}	1.25		1.43		1.67		ns
t _{CLRP}	0.20		0.20		0.20		ns
t _{PREP}	0.20		0.20		0.20		ns
t _{ESBCH}	1.25		1.43		1.67		ns
t _{ESBCL}	1.25		1.43		1.67		ns
t _{ESBWP}	1.28		1.51		1.65		ns
t _{ESBRP}	1.11		1.29		1.41		ns

Table 101. EF	20K1000E Ext	ernal Timing	Parameters				
Symbol	-1 Speed Grade		-2 Spee	-2 Speed Grade		Grade	Unit
	Min	Max	Min	Max	Min	Max	
t _{INSU}	2.70		2.84		2.97		ns
t _{INH}	0.00		0.00		0.00		ns
t _{outco}	2.00	5.75	2.00	6.33	2.00	6.90	ns
t _{INSUPLL}	1.64		2.09		-		ns
t _{INHPLL}	0.00		0.00		-		ns
t _{outcopll}	0.50	2.25	0.50	2.99	-	-	ns